CE EMC

TEST REPORT

For

Industrial System

Model: ARS-640M-845-X30-W; ARW-640M-XXX-YXX-Z (W=S or C, XXX=0-9, Y=A-Z, Z=B or W)

Trade Name: AAEON

Issued for

AAEON Technology Inc. 5F, No.135, Lane 235, Pao Chiao Rd., Hsin-Tien City, Taipei, Taiwan, R.O.C.

Issued by



Compliance Certification Services Inc. Hsintien Lab.

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Date of Issue: October 4, 2004

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1 TEST RESULT CERTIFICATION

Applicant: AAEON Technology Inc.

5F, No.135, Lane 235, Pao Chiao Rd., Hsin-Tien City,

Date of Issue: October 4, 2004

Taipei, Taiwan, R.O.C.

Manufacturer: AAEON Technology Inc.

5F, No.135, Lane 235, Pao Chiao Rd., Hsin-Tien City,

Taipei, Taiwan, R.O.C.

Equipment Under Test: Industrial System

Trade Name: AAEON

Model: ARS-640M-845-X30-W;

ARW-640M-XXX-YXX-Z

(W=S or C, XXX=0-9, Y=A-Z, Z=B or W)

Detailed EUT Description: See Item 2 of this report

Date of Test: September 30, 2004 & October 1, 2004

Applicable Standard	Class/Limit/Criterion	Test Result		
EN 55022: 1998 + A1: 2000	Class A	No non-compliance noted		
EN 61000-3-2: 2000	Class D	No non-compliance noted		
EN 61000-3-3: 1995 + A1: 2001	Limit	No non-compliance noted		
EN 55024:1998 + A1: 2001 + A2: 2003, including	ng			
IEC 61000-4-2: 1995 +A1: 1998 +A2: 2000	Criterion B	No non-compliance noted		
IEC 61000-4-3: 1995 +A1: 1998 +A2: 2000	Criterion A	No non-compliance noted		
IEC 61000-4-4: 1995 +A1: 2000	Criterion B	No non-compliance noted		
IEC 61000-4-5: 1995 +A1: 2000	Criterion B	No non-compliance noted		
IEC 61000-4-6: 1996 +A1: 2000	Criterion A	No non-compliance noted		
IEC 61000-4-8: 1993 +A1: 2000	Criterion A	No non-compliance noted		
IEC 61000-4-11: 1994 +A1: 2000	Criterion B/C/C	No non-compliance noted		
Deviation fr	Deviation from Applicable Standard			
None				

The above equipment was tested by Compliance Certification Services Inc. for compliance with the requirements set forth in the EMC Directive 89/336/EMC and the technical standards mentioned above. The results of testing in this report apply only to the product/system, which was tested. Other similar equipment will not necessarily produce the same results due to production tolerance and measurement uncertainties.

Approved by:

Reviewed by:

David Wang

Manager of Hsintien Laboratory

Compliance Certification Services Inc.

Vince Chiang

Section Manager of Hsintlen Laboratory

Compliance Certification Services Inc.

2 EUT DESCRIPTION

Product	Industrial System	
Trade Name	AAEON	
Model	ARS-640M-845-X30-W; ARW-640M-XXX-YXX-Z (W=S or C, XXX=0-9, Y=A-Z, Z=B or W)	
Housing Type	Metal case	
Power Adaptor Power Rating	100-240VAC, 50-60Hz	
AC Power During Test	230VAC / 50 Hz to AC Adaptor	
Power Supply Manufacturer	Seventeam	
Power Supply Model Number	ST-302HLP	
AC Power Cord Type	Unshielded, 1.8m (Detachable)	
OSC/Clock Frequency	32.768kHz; 14.318MHz; 24.576MHz; 25MHz	

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Model Differences:

Model Name	Difference	Tested (Checked)
ARS-640M-845-X30-W	Original	
ARW-640M-XXX-YXX-Z (W=S or C, XXX=0-9, Y=A-Z, Z=B or W)	For marketing purpose only.	

I/O PORT OF EUT

I/O PORT TYPE	Q'TY	TESTED WITH
1). PIO Port	1	1
2). SIO Port	1	1
3). PS/2 Keyboard Port	1	1
4). PS/2 Mouse Port	1	1
5). VIDEO-OUT Port (VGA)	1	1
6). AUDIO IN Port	1	1
7). Microphone Port	1	1
8). Earphone Port	2	2
9). LAN Port	1	1
10). USB 2.0 Port	3	3
11). Game Port	1	1

 $\textbf{\textit{Note:} Client consigns only one model sample (Model Number is ARS-640M-845-X30-W) to test.}$

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3 TEST METHODOLOGY

3.1 EUT SYSTEM OPERATION

- 1. Windows XP boots system.
- 2. Run Emctest.exe choose Elements / Video Mode to test.
- 3. Run Emitest.exe choose "0" Run All test.
- 4. Run F.bat and G.bat to test USB 2.0 Flash Disk.
- 5. Run Windows media player to play music.
- 6. Press the start menu, select executive and type ping 192.168.0.2 –t(EUT), ping 192.168.0.1 –t(Server Notebook).

Note: Test program is self-repeating throughout the test.

3.2 DECISION OF FINAL TEST MODE

1. The following test mode(s) were scanned during the preliminary test:

Mode(s):

- 1. 2048X1536, VF=75Hz
- 2. 1600X1200, VF=72Hz
- 3. 1280X1024, VF=70Hz
- 4. 800X600, VF=60Hz
- 2. After the preliminary scan, the following test mode(s) was found to produce the highest emission level.

Conduction: Mode 1 **Radiation:** Mode 1

Then, the EUT configuration and cable configuration of the above highest emission mode was chosen for all final test items.

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4 SETUP OF EQUIPMENT UNDER TEST

Setup Diagram

See test photographs attached in Appendix I for the actual connections between EUT and support equipment.

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Support Equipment

Host PC Devices:

No	Equipment	Model #	Serial #	FCC/BSMI ID	Trade Name
1	CPU (2.4GHz)	Celeron	N/A	N/A	Inter
2	RAM (256MB/DDR-400)	UG732D6688KS-GJ	N/A	N/A	Hynix
3	CD-ROM	CD-540E	N/A	N/A	TEAC
4	FDD	FDD-235HF	N/A	N/A	TEAC
5	HDD	ST36422A	N/A	N/A	Seagate
6	Power Supply	ST-302HLP	N/A	N/A	Seventeam
7	Motherboard	MB-845GE RevA1.0	N/A	N/A	CHAINTECH

Peripherals Devices:

No	Equipment	Model	Serial No.	FCC/ BSMI ID	Trade Name	Data Cable	Power Cord
1	Player	RQ-L11LT	N/A	BSMI ID: 3913A162	Panasonic	Unshielded, 1.0m	N/A
2	USB Mouse	M-BE58	LZE22351631	BSMI ID: 3892A471	Logitech	Shielded, 1.8m	N/A
3	PS/2 Mouse	M-S34	LNA12301809	BSMI ID: 4862A011 DZL211029	Logitech	Shielded, 1.8m	N/A
4	PS/2 Keyboard	Y-SP29	SYU25038728	BSMI ID: 3902C736	Logitech	Shielded, 1.8m	N/A
5	Ear. / Mic.	N/A	N/A	N/A	N/A	Unshielded, 1.7m	N/A
6	Ear.	Axis-301	N/A	N/A	LABTEC	Unshielded, 1.7m	N/A
7	Joystick	G-ZA-PHI	PHB03800086	BSMI ID: 4882A142	Logitech	Shielded, 2.6m	N/A
8	Printer	C20SX	N/A	BSMI ID: 3902E004	EPSON	Shielded, 1.8m	Unshielded, 1.8m
9	USB 2.0 Flash Disk	TS128MJF2A	N/A	BSMI ID: D33193	Transcend	N/A	N/A
10	USB 2.0 Flash Disk	TS128MJF2A	N/A	BSMI ID: D33193	Transcend	N/A	N/A
11	Modem	5JEG4033MKO	N/A	5RJTAI-35500-M5-E	TOP - SOLUTION	Shielded, 1.2 m	Unshielded, 1.8m
12	Monitor	CPD-G500	2737928	DoC BSMI ID: 3882B314	SONY	Shielded, 1.8m with two cores	Unshielded, 1.8m
13	Server Notebook	M285	RD49R-7YTJR- B3C4K-G2JQX- DD3CG	DoC BSMI ID: R31259	LEO	Unshielded, 10m	Unshielded, 1.8m with a core

Note: All the above equipment/cables were placed in worse case positions to maximize emission signals during emission test. Grounding: Grounding was in accordance with the manufacturer's requirements and conditions for the intended use.

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5 FACILITIES AND ACCREDITATIONS

5.1 FACILITIES

All measurement facilities used to collect the measurement data are located at CCS Taiwan Hsintien Lab at No. 165, Chunghsen Road, Hsintien City, Taipei Hsien, Taiwan.

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The measurement facilities are constructed in conformance with the requirements of CISPR 16-1, ANSI C63.4 and other equivalent standards.

5.2 LABORATORY ACCREDITATIONS AND LISTINGS

The test facilities used to perform Electromagnetic compatibility tests are registered or accredited by the organizations listed in the following table which includes the recognized scope specifically.

Country	Agency	Scope of Accreditation	Logo
USA CFR 47, FCC Part 15/18 using ANSI 63.4; AS/NZS 3548; VCCI V3; CNS 13438; CNS 13439; CNS 13783; CNS 1411 CISPR 11/EN 55011; CISPR 14-1/EN 55014-1; CISPR 15/EN 55015; CISPR 22/EN 55022; EN 50081-1/EN 61000-6-3; EN 50082-1/EN 61000-6-4; IEC/EN 61000-4-2, IEC/EN 61000-4-3, IEC/EN 61000-4-4, IEC/EN 61000-4-5, IEC/EN 61000-4-6, IEC/EN 61000-4-8, IEC/EN 61000-4-1 IEC/EN 61000-3-2, IEC/EN 61000-3-3; CISPR 24/EN 5502 CISPR 14-2/EN 55014-2; EN 50081-2/EN 61000-6-1; EN 50082-2/EN 61000-6-2.		ACCREDITED	
USA	FCC	3/10 meter Open Area Test Sites to perform FCC Part 15/18 measurements	FC 250366
Japan	VCCI	3/10 meter Open Area Test Sites and Line Conducted Test Room to perform conducted/radiated measurements	VCCI R-1434/1630~4 C-1511/1882
Norway	NEMKO	EN 50081-1/2, EN 50082-1/2, IEC 61000-6-1/2/3/4, EN 50091-2, EN 50130-4, EN 55011, EN 55013, EN 55014-1/2, EN 55015, EN 55022, EN 55024, EN 61000-3-2/3, EN 61326-1, IEC 61000-4-2/3/4/5/6/8/11, Cispr 16-1/2/3/4	N ELA 103
Taiwan	CNLA	47 CFR FCC Part 15 Subpart B, EN 61000-3-2, EN 61000-3-3, CNS 13439, CNS 13783-1, CNS 13438, AS/NZS 3548, VCCI, CNS 13022-1/2/3, EN 55022, EN 55013, EN 55014-1, EN 61000-4-2/3/4/5/6/8/11, ENV 50204, ENV 50141, ENV 50142	1108 ILAC MRA
Taiwan	BSMI	CNS 13438, CNS 13783-1, CNS 13439	SL2-IN-E-0005 SL2-A1-E-0005 SL2-R1-E-0005 SL2-R2-E-0005

Note: No part of this report may be used to claim or imply product endorsement by CNLA, A2LA or other government agency.

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6 INSTRUMENT AND CALIBRATION

6.1 MEASURING INSTRUMENT CALIBRATION

The measuring equipment utilized to perform the tests documented in this report has been calibrated once a year or in accordance with the manufacturer's recommendations, and is traceable to recognized national standards.

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6.2 TEST AND MEASUREMENT EQUIPMENT

The following list contains measurement equipment used for testing. The equipment conforms to the requirement of CISPR 16-1, ANSI C63.2 and. other required standards.

Calibration of all test and measurement, including any accessories that may effect such calibration, is checked frequently to ensure the accuracy. Adjustments are made and correction factors are applied in accordance with the instructions contained in the respective manual.

Equipment Used for Emission Measurement

Open Area Test Site # I					
EQUIPMENT	MFR	MODEL	SERIAL NUMBER	CAL. DUE	
SITE NSA	CCS	I Site	N/A	09/17/2005	
MEASURE RECEIVER	SCHAFFNER	SCR3501	338	07/05/2005	
SPECTRUM ANALYZER	ADVANTEST	R3132	120900008	No Calibration Required	
ANTENNA	SCHAFFNER	CBL 6112B	2809	09/26/2005	
AMPLIFIER	SCHAFFNER	CPA9231A	3626	10/10/2004	
CABLE	BELDEN	9913	N-TYPE #I1	10/10/2004	
ATTENUATOR	MCL	UNAT-6	AT06-3	10/10/2004	
THERMO- HYGRO METER	TFA	N/A	NO.2	11/23/2004	
DECOUPLING NETWORK	FCC	F-201-DCN-5-6MM	22、24	09/07/2005	

Note: The measurement uncertainty is less than +/- 3.36dB, which is evaluated as per the NAMAS NIS 81 and CISPR/A/291/CDV.

Conducted Emission Test Site # A					
EQUIPMENT	MFR	MODEL	SERIAL NUMBER	CAL. DUE	
TEST RECEIVER	R&S	ESHS20	840455/006	03/07/2005	
LISN (EUT)	SCHWARZBECK	NSLK 8127	8127382	01/05/2005	
LISN	SOLAR	8012-50-R-24-BNC	8305114	02/10/2005	
BNC CABLE	MIYAZAKI	5D-FB	BNC A1	01/30/2005	
THERMO- HYGRO METER	ТОР	HA-202	9303-1	03/24/2005	
4-Wire ISN	R&S	ENY41	100006	07/01/2005	
2-Wire ISN	R&S	ENY22	100020	07/01/2005	

Note: The measurement uncertainty is less than +/- 2.83dB, which is evaluated as per the NAMAS NIS 81 and CISPR/A/291/CDV.

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Power Harmonic & Voltage Fluctuation/Flicker Test Site (EN 61000-3-2&-3-3)					
Manufacturer/Type	Cal. Due				
Schaffner / Signal Conditioning Unit	CCN 1000-1	72122	12/02/2004		
Schaffner / 5KVA AC Power Source	NSG 1007	55131	No Calibration Required		

Equipment Used for Immunity Measurement

ESD Test Site (EN 61000-4-2)						
Manufacturer/Type Model No. Serial No. Cal. Due						
Haefely / ESD Simulator	PESD 1600	C3010003	12/30/2004			
Stockburger / Aneroid Barometer	Barometer	9303	03/30/2005			
TOP / Thermo-Hygro meter	HA-202	9303-1	03/24/2005			

Radiated Electr	Radiated Electromagnetic Field Immunity Test Site (EN 61000-4-3)						
Manufacturer/Type	Model No.	Serial No.	Cal. Due				
Calibration of Field	Chamber#RS	RS3H-6 / RS3V-6	07/02/2005				
Agilent / Signal Generator	E4421B	MY43350597	05/30/2005				
AR / Electric Field Probe	FP6001	305650	11/14/2004				
Boonton / RF Voltmeter	9200B	9200B 328001AE					
BNC / Function Generator	or 625 25451		02/18/2005				
AR / Amplifier	100W1000M1	17564	No Calibration Required				
Werlatone Inc. / Direction Coupler	C2630	4121	No Calibration Required				
Frankonia / Broadband Antenna	BTA-M	030001M	No Calibration Required				
TOP / Thermo-Hygro meter	HA-202	9303-2	03/24/2005				

Fast Transients/Burst Test Site (EN 61000-4-4)							
Manufacturer/Type Model No. Serial No. Cal. Due							
Schaffner / EFT Generator	BEST EMC V2.3	200031A024SC	11/17/2004				
Schaffner / Capacitive Clamp	N/A	N/A	No Calibration Required				

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Surge Immunity Test Site (EN 61000-4-5)							
Manufacturer/Type Model No. Serial No. Cal. Due							
Schaffner / Surger Generator	BEST EMC V2.3	200031A024SC	11/17/2004				
Schaffner / Signal and Data Lines Coupling Network	CDN118	19328	No Calibration Required				

CS test (EN 61000-4-6)					
Manufacturer/Type	Model No.	Serial No.	Cal. Due		
Schaffner / RF Generator	NSG 2070-1	1061	08/02/2005		
Schaffner / CDN	CDN M316	19600	08/02/2005		
Schaffner / CDN	CDN M216	19294	08/02/2005		
Schaffner / EM Clamp	KEMZ 801	KEMZ 801 19227			
Schaffner / CDN	CDN A800	CDN A800 17885			
Schaffner / CDN	CDN T002	15881	01/30/2005		
FCC / CDN	FCC-801-T8-RJ45	04025	06/24/2005		
Schaffner / Attenuator	INA2070-1	2061	No Calibration Required		
FCC / CDN	FCC-801-T4-RJ45	04031	08/19/2005		

Power Frequency Magnetic Field Immunity test (EN 61000-4-8)								
Manufacturer/Type Model No. Serial No. Cal. Due								
Schaffner / Induction Coil Interface	INA 21141	6009	No Calibration Required					
Schaffner / 5KVA AC Power Source	NSG 1007	55131	No Calibration Required					
CHY/ TRMS Clamp Meter	932C	2K0900285	10/16/2004					
Sypris / Magnetic Field Meter	4080	0247	02/11/2005					

Voltage Dips/Short Interruption and Voltage Variation Immunity test (EN 61000-4-11)							
Manufacturer/Type Model No. Serial No. Cal. Due							
Schaffner / Dips/Interruption/Variations Tester	BEST EMC V2.3	200031A024SC	11/17/2004				
Protronix / Digital Power Meter	1201	201091	08/31/2005				

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7 LINE CONDUCTED & RADIATED EMISSION TEST

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7.1 LIMIT

Maximum permissible level of Line Conducted Emission

FREQUENCY	Class A	(dBuV)	Class B (dBuV)		
(MHz)	Quasi-peak	Average	Quasi-peak	Average	
0.15 - 0.5	79	66	66 - 56	56 - 46	
0.50 - 5.0	73	60	56	46	
5.0 - 30.0	73	60	60	50	

Note: The lower limit shall apply at the transition frequency.

<u>Maximum permissible level of Common Mode Conducted Emission</u> (<u>Telecommunication Ports</u>)

CLASS A

FREQUENCY	Voltage Limit (dBuV)		Current Limit (dBuA)	
(MHz)	Quasi-peak Average		Quasi-peak	Average
0.15 - 0.5	97 – 87	84 - 74	53 – 43	40 – 30
0.5 - 30.0	87	74	43	30

CLASS B

FREQUENCY	Voltage Limit (dBuV)		Current Limit (dBuA)		
(MHz)	Quasi-peak Average		Quasi-peak	Average	
0.15 - 0.5	84 - 74	74 - 64	40 – 30	30 - 20	
0.5 - 30.0	74 64 30		30	20	

Note: The lower limit shall apply at the transition frequency.

Maximum permissible level of Radiated Emission measured at 10 meter

FREQUENCY	Class A (dBuV/m)	Class B (dBuV/m)
(MHz)	Quasi-peak	Quasi-peak
30 – 230	40	30
230 - 1000	47	37

Note: The lower limit shall apply at the transition frequency.

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7.2 TEST PROCEDURE OF LINE CONDUCTED EMISSION

Procedure of Preliminary Test

• The EUT was set up as per the test configuration to simulate typical usage per the user's manual. When the EUT is a tabletop system, a wooden table with a height of 0.8 meters is used and is placed on the ground plane as per EN 55022 (see Test Facility for the dimensions of the ground plane used). When the EUT is a floor-standing equipment, it is placed on the ground plane which has a 3-12 mm non-conductive covering to insulate the EUT from the ground plane.

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- Support equipment, if needed, was placed as per EN 55022.
- All I/O cables were positioned to simulate typical actual usage as per EN 55022.
- The test system with EUT received AC power, 230V/50Hz, through a Line Impedance Stabilization Network (LISN), which supplied power source and was grounded to the ground plane.
- All support equipment received power from a second LISN.
- The EUT test program was started. Emissions were measured on each current carrying line of the EUT using an EMI Test Receiver connected to the LISN powering the EUT.
- The Receiver scanned from 150kHz to 30MHz for emissions in each of the test modes.
- During the above scans, the emissions were maximized by cable manipulation.
- The test mode(s) described in Item 3.2 were scanned during the preliminary test.
- After the preliminary scan, we found the test mode described in Item 3.2 producing the highest emission level.
- The EUT configuration and cable configuration of the above highest emission level were recorded for reference of the final test.

Procedure of Final Test

- EUT and support equipment were set up on the test bench as per the configuration with highest emission level in the preliminary test.
- A scan was taken on both power lines, Line 1 and Line 2, recording at least the six highest emissions. Emission frequency and amplitude were recorded into a computer in which correction factors were used to calculate the emission level and compare reading to the applicable limit. If EUT emission level was less –2dB to the Average limit in Q.P. mode, then the emission signal was re-checked using an Average detector.
- The test data of the worst-case condition(s) was recorded.

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Data Sample:

Freq. MHz	Read Level dBuV	Factor dB	Level dBuV	Limit dBuV	Over Limit dB	Reading Type (P/Q/A)	Line (L1/L2)
x.xx	42.95	0.55	43.50	73	-29.50	Q	L1

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Freq. = Emission frequency in MHz

Read Level = Uncorrected Analyzer/Receiver reading Factor = Insertion loss of LISN + Cable Loss

Level = Read Level + Factor Limit = Limit stated in standard Over Limit = Reading in reference to limit

P = Peak Reading

Q = Quasi-peak Reading A = Average Reading

L1 = Hot side L2 = Neutral side

Calculation Formula

Over Limit (dB) = Level (dBuV) – Limit (dBuV)

7.3 TEST PROCEDURE OF COMMON MODE CONDUCTED EMISSION FOR TELECOMMUNICATION PORT

- Selecting ISN for unscreened cable or a current probe for screened cable to take measurement.
- The port of the EUT was connected to the remote side support equipment through the ISN/Current Probe and communication in normal condition.
- Making a overall range scan by using the test receiver controlled by controller and record at least six highest emissions for showing in the test report.
- Emission frequency and amplitude were recorded into a computer in which correction factors were used to calculate the emission level and compare reading to the applicable limit.
- In case of measuring on the screened cable, the current limit shall be applied, otherwise the voltage limit should be applied.
- The following test mode(s) were scanned during the preliminary test:

Mode(s):

- 1 10 Mbps
- 2 100 Mbps
- After the preliminary scan, we found the following test mode(s) producing the highest emission level and test data of the worst case was recorded.

Mode: 1.

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Data Sample:

Freq. MHz	Read Level dBuV	Factor dB	Level dBuV	Limit dBuV	Over Limit dB	Reading Type (P/Q/A)
X.XX	62.95	0.55	63.50	87	-23.50	Q

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Freq. = Emission frequency in MHz

Read Level = Uncorrected Analyzer/Receiver reading Factor = Insertion loss of ISN + Cable Loss

Level = Read Level + Factor
Limit = Limit stated in standard
Over Limit = Reading in reference to limit

P = Peak Reading Q = Quasi-peak Reading A = Average Reading

Calculation Formula

Over Limit (dB) = Level (dBuV) – Limit (dBuV)

7.4 TEST PROCEDURE OF RADIATED EMISSION

Procedure of Preliminary Test

- The equipment was set up as per the test configuration to simulate typical usage per the user's manual. When the EUT is a tabletop system, a wooden turntable with a height of 0.8 meters is used which is placed on the ground plane. When the EUT is a floor-standing equipment, it is placed on the ground plane which has a 3-12 mm non-conductive covering to insulate the EUT from the ground plane.
 - Support equipment, if needed, was placed as per EN 55022.
 - All I/O cables were positioned to simulate typical usage as per EN 55022.
 - The EUT received AC power source, 230V/50Hz, from the outlet socket under the turntable. All support equipment received power from another socket under the turntable.
 - Mains cables, telephone lines or other connections to auxiliary equipment located outside the
 test are shall drape to the floor, be fitted with ferrite clamps or ferrite tubes placed on the floor
 at the point where the cable reaches the floor and then routed to the place where they leave the
 turntable. No. extension cords shall be used to mains receptacle.
 - The antenna was placed at 10 meter away from the EUT as stated in EN 55022. The antenna connected to the Spectrum Analyzer via a cable and at times a pre-amplifier would be used.
 - The Analyzer / Receiver quickly scanned from 30MHz to 1000MHz. The EUT test program was started. Emissions were scanned and measured rotating the EUT to 360 degrees and positioning the antenna 1 to 4 meters above the ground plane, in both the vertical and the horizontal polarization, to maximize the emission reading level.

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- The test mode(s) described in Item 3.2 were scanned during the preliminary test:
- After the preliminary scan, we found the test mode described in Item 3.2 producing the highest emission level.
- The EUT and cable configuration, antenna position, polarization and turntable position of the above highest emission level were recorded for the final test.

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Procedure of Final Test

- EUT and support equipment were set up on the turntable as per the configuration with highest emission level in the preliminary test.
- The Analyzer / Receiver scanned from 30MHz to 1000MHz. Emissions were scanned and measured rotating the EUT to 360 degrees, varying cable placement and positioning the antenna 1 to 4 meters above the ground plane, in both the vertical and the horizontal polarization, to maximize the emission reading level.
- Recorded at least the six highest emissions. Emission frequency, amplitude, antenna position, polarization and turntable position were recorded into a computer in which correction factors were used to calculate the emission level and compare reading to the applicable limit and only Q.P. reading is presented.

Data Sample:

Freq. MHz	Amptd dBuV/m	Margin dB	Limit dBuV/m	Reading dBuV	Factor dB/m	Reading Type (P/Q/A)	Pol. (H/V)
x.xx	26.2	-13.8	40	14	12.2	Q	Н

Freq. = Emission frequency in MHz

Reading = Uncorrected Analyzer/Receiver reading

Factor = Antenna Factor + Cable Loss + Attenuator (3/6/10dB) – Amplifier Gain

Amptd = Uncorrected Analyzer/Receiver reading + Factor

Limit = Limit stated in standard

Margin = Reading in reference to limit

P = Peak Reading

Q = Quasi-peak Reading A = Average Reading

H = Antenna Polarization: Horizontal V = Antenna Polarization: Vertical

Calculation Formula

Margin (dB) = Amptd (dBuV/m) – Limit (dBuV/m)

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7.5 TEST RESULTS

Line Conducted Emission

Model: ARS-640M-845-X30-W Test Mode: Mode 1

Temperature: 26 °C **Humidity:** 64% RH

Test Results: Passed **Tested by:** John Yen

(The chart below shows the highest readings taken from the final data, see Appendix III for details.)

Six Highest Conducted Emission Readings								
Fre	quency Ran	ge Investiga	ated	150 kHz to 30 MHz				
Freq (MHz)	Read Level (dBuV)	Factor (dB)	Level (dBuV)	Limit Line (dBuV)	Over Limit (dB)	Reading Type (P/Q/A)	Line (L1/L2)	
3.140	33.07	0.23	33.30	73.00	-39.70	P	L1	
10.125	40.35	0.51	40.86	73.00	-32.14	P	L1	
20.270	46.41	0.89	47.30	73.00	-25.70	P	L1	
3.224	33.77	0.24	34.01	73.00	-38.99	P	L2	
9.966	41.25	0.51	41.76	73.00	-31.24	P	L2	
19.950	47.19	0.87	48.07	73.00	-24.93	P	L2	

NOTE: The emission level was or more than 2dB below the Average limit, so no re-check anymore.

Common Mode Conducted Emission

Six Highest Conducted Emission Readings							
Frequency Range Investigated				150 kHz to 30 MHz			
Freq (MHz)	Read Level (dBuV)	Factor (dB)	Level (dBuV)	Limit Line (dBuV)	Over Limit (dB)	Reading Type (P/Q/A)	
0.211	41.45	10.30	51.75	94.18	-42.43	P	
0.317	43.19	10.30	53.49	90.80	-37.31	P	
0.421	37.21	10.30	47.51	88.42	-40.91	P	
0.532	38.31	10.29	48.60	87.00	-38.40	P	
10.233	42.33	10.20	52.53	87.00	-34.47	P	
18.039	44.09	10.20	54.29	87.00	-32.71	P	

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Radiated Emission

Model: ARS-640M-845-X30-W Test Mode: Mode 1

Temperature: 24°C **Humidity:** 62% RH

Test Results: Pass **Tested by:** Matt Hsu

(The chart below shows the highest readings taken from the final data, see Appendix III for details.)

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Six Highest Radiated Emission Readings								
Frequency	Range Inve	estigated		30 N	MHz to 1000	MHz at 10	m	
Freq Amptd Margin Limit (MHz) (dBuV/m) (dB) (dBuV/m)			Limit (dBuV/m)	Reading (dBuV)	Factor (dB/m)	Reading Type (P/Q/A)	Pol. (H/V)	
67.7810	35.29	-4.71	40.00	51.10	-15.81	P	V	
159.7300	30.98	-9.02	40.00	41.65	-10.67	P	V	
800.3200	42.54	-4.46	47.00	40.11	2.43	P	V	
124.4900	27.52	-12.48	40.00	36.85	-9.33	P	H	
599.4000	40.92	-6.08	47.00	40.21	0.71	P	H	
800.9000	38.65	-8.35	47.00	36.21	2.44	P	H	

NOTE: None.

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8 POWER HARMONICS TEST

Port : AC mains

Basic Standard : EN 61000-3-2 (2000)

Limits : \square CLASS A; \overline{V} CLASS D

Teste d by : Jason Lee

Temperature : 20°C **Humidity** : 59%

Limit:

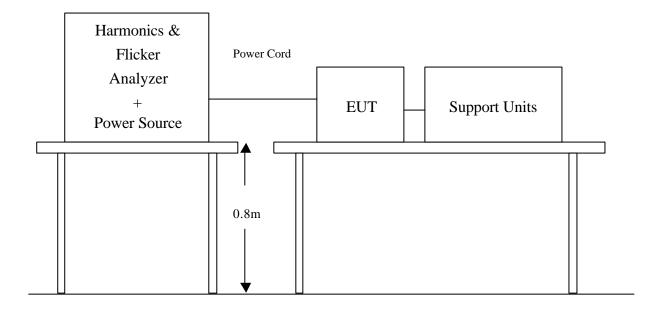
Limits for Class A equipment				
Harmonics	Max. permissible			
Order	harmonics current			
n	A			
Od	d harmonics			
3	2.30			
5	1.14			
7	0.77			
9	0.40			
11	0.33			
13	0.21			
15<=n<=39	0.15x15/n			
Eve	en harmonics			
2	1.08			
4	0.43			
6 0.30				
8<=n<=40	0.23x8/n			

Limits for Class D equipment						
Harmonics Order n	Max. permissible harmonics current per watt mA/W	Max. permissible harmonics current				
	Odd Harmonics only	7				
3	3.4	2.30				
5	1.9	1.14				
7	1.0	0.77				
9	0.5	0.40				
11	0.35	0.33				
13	0.30	0.21				
15<=n<=39	3.85/n	0.15x15/n				

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Block Diagram of Test Setup:



Test Procedure:

- a. The EUT was placed on the top of a wooden table 0.8 meters above the ground and operated to produce the maximum harmonic components under normal operating conditions for each successive harmonic component in turn.
- b. The correspondent test program of test instrument to measure the current harmonics emanated from EUT is chosen. The measure time shall be not less than the time necessary for the EUT to be exercised.

<u>Test Result</u>: (See Appendix II for details)

Note: No function degraded during the tests.	

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9 POWER VOLTAGE FLUCTUATION / FLICKER TEST

Port : AC mains

Basic Standard : EN 61000-3-3 (1995 + A1: 2001)

Limits : § of EN 61000-3-3

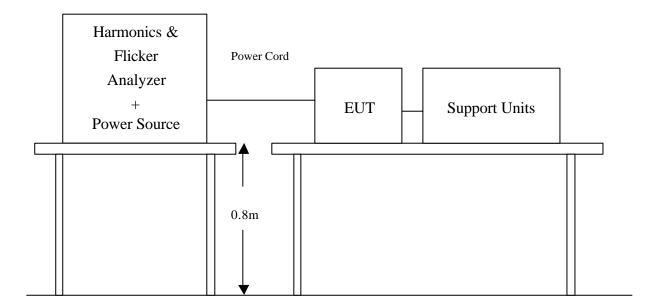
Teste d by : Jason Lee

Temperature : 20°C **Humidity** : 59%

Limit:

TEST ITEM LIMIT		REMARK		
P _{st}	1.0	P _{st} means short-term flicker indicator.		
P _{lt} 0.65		P _{lt} means long-term flicker indicator.		
T _{dt} (ms) 500		T_{dt} means maximum time that dt exceeds 3.3 %.		
d _{max} (%)	4%	d _{max} means maximum relative voltage change.		
dc (%)	3.3%	dc means relative steady-state voltage change		

Block Diagram of Test Setup:



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Test Procedure:

a. The EUT was placed on the top of a wooden table 0.8 meters above the ground and operated to produce the most unfavorable sequence of voltage changes under normal operating conditions.

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b. During the flick measurement, the measure time shall include that part of whole operation cycle in which the EUT produce the most unfavorable sequence of voltage changes. The observation period for short-term flicker indicator is 10 minutes and the observation period for long-term flicker indicator is 2 hours.

Test Result: (See Appendix II for details)

TEST PARAMETER	MEASUREMENT VALUE	LIMIT	RESULT
P_{st}	0.162	1.0	Pass
P_{lt}	0.071	0.65	Pass
T _{dt} (ms)	0.0	500	Pass
d _{max} (%)	0.57	4%	Pass
dc (%)	0.40	3.3%	Pass

Note: None.

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10 ELECTROSTATIC DISCHARGE (ESD) IMMUNITY TEST

Port : Enclosure

Basic Standard: IEC/EN 61000-4-2

Test Level : $\pm 8 \text{ kV (Air Discharge)}$

±4 kV (Contact Discharge)

±4 kV (Indirect Discharge)

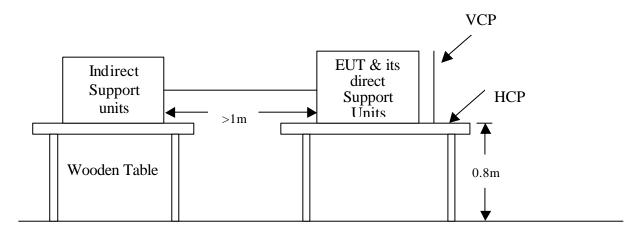
Performance Criterion: B (Standard Required)

Tested by : Jason Lee
Temperature : 20°C
Humidity : 49%

Pressure : 1012mbar

Block Diagram of Test Setup:

(The 470 k ohm resistors are installed per standard requirement.)



Ground Reference Plane

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Test Procedure:

- 1. The EUT was located 0.1 m minimum from all side of the HCP.
- 2. The indirect support units were located 1 m minimum away from the EUT, but direct support unit was/were located at same location as EUT on the HCP and keep at a distance of 10 cm with EUT.

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- 3. As per the requirement of EN 55024; applying direct contact discharge at the sides other than front of EUT at minimum 50 discharges (25 positive and 25 negative) if applicable, can't be applied direct contact discharge side of EUT then the indirect discharge shall be applied. One of the test points shall be subjected to at least 50 indirect discharge (contact) to the front edge of horizontal coupling plane.
- 4. Other parts of EUT where it is not possible to perform contact discharge then selecting appropriate points of EUT for air discharge, a minimum of 10 single air discharges shall be applied.
- 5. The application of ESD to the contact of open connectors is not required.
- 6. The EUT direct connection units also need to be applied ESD at the port of EUT cable connected.
- 7. Putting a mark on EUT to show tested points. The following test condition was followed during the tests.

Note: As per IEC/EN 61000-4-2, two 470k bleed resistors cable is connected between the EUT and HCP during the test applicable for power ungrounded or battery operating unit only.

The electrostatic discharges were applied as follows:

Amount of discharge	Voltage	Coupling	Result (Pass/Fail)
Mini 10 /Point	$\pm 8 \text{ kV}$	Air Discharge	Pass
Mini 25 /Point	±4 kV	Contact Discharge	Pass
Mini 25 /Point	±4 kV	Indirect Discharge HCP (Front)	Pass
Mini 25 /Point	±4 kV	Indirect Discharge VCP (Right)	Pass
Mini 25 /Point	$\pm 4 \text{ kV}$	Indirect Discharge VCP (Left)	Pass
Mini 25 /Point	$\pm4\;kV$	Indirect Discharge VCP (Back)	Pass

^{**}For the tested points to EUT, please refer to attached page.
(Blue arrow mark for contact discharge and red arrow mark for air discharge)

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Performance & Result:

	Criterion A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.					
	Criterion B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.					
	Criterion C: Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.						
Oł	Observation: No function degraded during the tests.						

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The Tested Points of EUT

Photo 1 of 5



Photo 2 of 5



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Photo 3 of 5



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Photo 5 of 5



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11 RADIATED ELECTROMAGNETIC FIELD IMMUNITY TEST

Port : Enclosure

Basic Standard: IEC/EN 61000-4-3

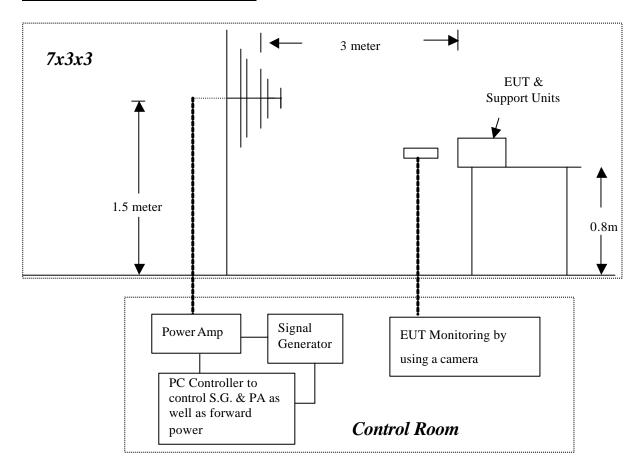
Requirements : 3 V/m / with 80% AM. 1kHz Modulation.

Performance Criterion: A (Standard Required)

Tested by : Jason Lee
Temperature : 20°C
Humidity : 59%

Pressure : 1012mbar

Block Diagram of Test Setup:



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Test Procedure:

1. The EUT and support units were located at the edge of supporting table keep 3 meter away from transmitting antenna, it just the calibrated square area of field uniformity.

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- 2. Adjusting the cables to be exposed to the electromagnetic filed as possible.
- 3. Performing a Radiated Emission Scan in range of 30 to 1000 MHz prior to do RS test and records the more higher emission frequencies for the reference of RS test, due to antenna effectiveness.
- 4. Adjusting the monitoring camera to monitor the "H" message as clear as possible.
- 5. Setting the testing parameters of RS test software per IEC 61000-4-3.
- 6. Referring to the tested data of step 3 to performing the RS test from 80 to 1000 MHz.
- 7. Recording the test result in following table.
- 8. Changing the EUT to the other side and repeat step 3 to 6, until 4 sides of EUT were verified.

IEC 61000-4-3 Final test conditions:

Test level : 3V/m

Steps : 1 % of fundamental

Dwell Time : 3 sec

Range (MHz)	Field	Modulation	Polarity	Position (°)	Result (Pass/Fail)
80-1000	3V	Yes	Н	Front	Pass
80-1000	3V	Yes	V	Front	Pass
80-1000	3V	Yes	Н	Right	Pass
80-1000	3V	Yes	V	Right	Pass
80-1000	3V	Yes	Н	Back	Pass
80-1000	3V	Yes	V	Back	Pass
80-1000	3V	Yes	Н	Left	Pass
80-1000	3V	Yes	V	Left	Pass

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Performance & Result:

	Criterion A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.	
	Criterion B: The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatused as intended. In some cases the performance level may be reported by a permissible loss of performance. During the test, degradation performance is however allowed.		
	Criterion C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.	
Observation: No function degraded during the tests.			

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12 FAST TRANSIENTS/BURST IMMUNITY TEST

Port : On Power Supply Lines and Data Line

Basic Standard: IEC/EN 61000-4-4

Requirements : $\pm 1 \text{ kV}$ for Power Supply Line

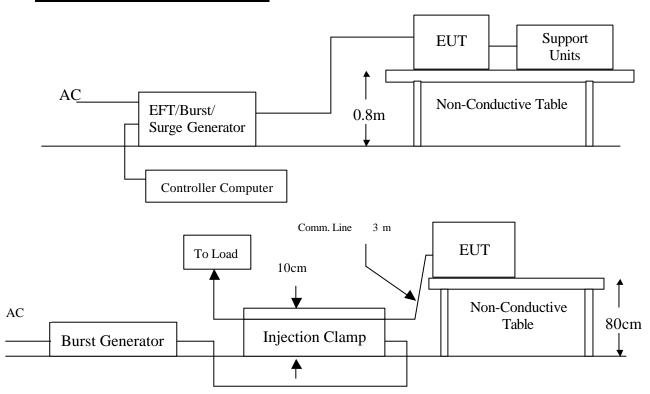
± 0.5kV to Data Line

Performance Criteria: B (Standard Required)

Tested by : Jason Lee
Temperature : 20°C
Humidity : 59%

Pressure : 1012mbar

Block Diagram of Test Setup:



Test Procedure:

- 1. The EUT and support units were located on a wooden table 0.8 m away from ground reference plane.
- 2. A 1.0 meter long power cord was attached to EUT during the test.
- 3. The length of communication cable between communication port and clamp was keeping within 1 meter.
- 4. Injected test voltage to the EUT ports from minimum to standard request or client request.
- 5. Recorded the test result as shown in following table.

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Test conditions:

Impulse Frequency: 5kHz
Tr/Th:: 5/50ns
Burst Duration:: 15ms
Burst Period:: 3Hz

Inject Line	Voltage kV	Inject Method	Result (Pass/Fail)
L	± 1	Direct	Pass
N	± 1	Direct	Pass
PE	± 1	Direct	Pass
L+N	± 1	Direct	Pass
L + PE	± 1	Direct	Pass
N + PE	± 1	Direct	Pass
L + N + PE	± 1	Direct	Pass
RJ45	±0.5	Clamp	Pass

Date of Issue: October 4, 2004

Performance & Result:

	Criterion A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.	
	Criterion B: The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus used as intended. In some cases the performance level may be replated by a permissible loss of performance. During the test, degradation of performance is however allowed.		
	Criterion C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.	
Oł	Observation: No function degraded during the tests.		

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13 SURGE IMMUNITY TEST

Port : Power Cord

Basic Standard : IEC/EN 61000-4-5

Requirements : $\pm 1 \text{ kV}$ (Line to Line)

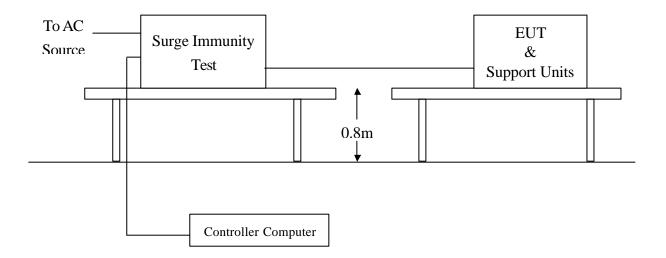
 \pm 2 kV (Line to Ground)

Performance Criteria: B (Standard Required)

Tested by : Jason Lee
Temperature : 20°C

Humidity : 59%
Pressure : 1012mbar

Block Diagram of Test Setup:



Test Procedure:

- 1. The EUT and support units were located on a wooden table 0.8 m away from ground floor.
- 2. Injected test voltage to the EUT ports from minimum to standard request or client request.
- 3. Recorded the test result as shown in following table.

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Test conditions:

Voltage Waveform : 1.2/50 usCurrent Waveform : 8/20 us

Polarity : Positive/Negative Phase angle : 0°, 90°, 270°

Number of Test : 5

Coupling Line	Voltage (kV)	Polarity	Coupling Method	Result (Pass/Fail)
L1-L2	1	Positive	Capacitive	Pass
L1-PE	2	Positive	Capacitive	Pass
L2-PE	2	Positive	Capacitive	Pass
L1-L2	1	Negative	Capacitive	Pass
L1-PE	2	Negative	Capacitive	Pass
L2-PE	2	Negative	Capacitive	Pass

Performance & Result:

\boxtimes	Criterion A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.	
	Criterion B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.	
	Criterion C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.	
	Observation: No function degraded during the tests.		

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14 CONDUCTED DISTRBANCE/INDUCED RADIO-FREQUENCY FIELD IMMUNITY TEST

Port : AC Port and Line Cable

Basic Standard: IEC/EN 61000-4-6

Requirements : 3 V, with 80% AM. 1kHz Modulation.

Injection Method : CDN-M3 for Power Cord

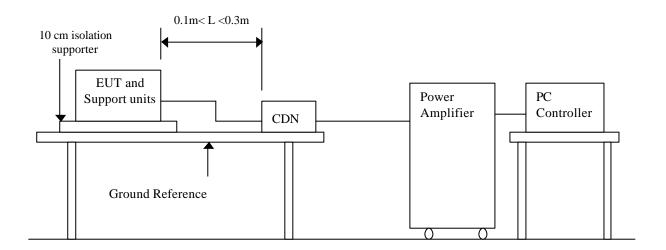
CDN-T4 for RJ45 Cable

Performance Criterion: A (Standard Required)

Tested by : Jason Lee
Temperature : 20°C
Humidity : 59%

Pressure : 1012mbar

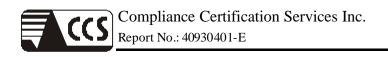
Block Diagram of Test Setup:



Test Procedure:

- 1. The EUT and support units were located at a ground reference plane with the interposition of a 0.1 m thickness insulating support and the CDN was located on GRP directly.
- 2. Set the testing parameters of CS test software as per IEC/EN 61000-4-6.
- 3. Recorded the test result in following table.

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Test conditions:

Frequency Range : 0.15MHz-80MHz Frequency Step : 1% of fundamental

Dwell Time : 3 sec

Range (MHz)	Field	Modulation	Result (Pass/Fail)
0.15-80	3V	Yes	Pass

Date of Issue: October 4, 2004

Performance & Result:

\boxtimes	Criterion A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.	
	Criterion B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.	
	Criterion C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.	
Oł	Observation: No function degraded during the tests.		

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15 POWER FREQUENCY MAGNETIC FIELD IMMUNITY TEST

Date of Issue: October 4, 2004

Port : Enclosure

Basic Standard: IEC/EN 61000-4-8

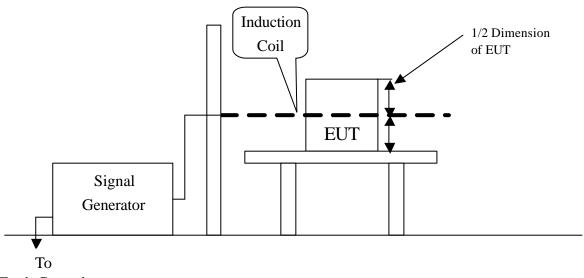
Requirements : 1 A/m

Performance Criterion: A (Standard Required)

Tested by : Jason Lee
Temperature : 20°C
Humidity : 59%

Pressure : 1012mbar

Block Diagram of Test Setup:



Earth Ground

Test Procedure:

- 1. The EUT and support units were located on Ground Reference Plane with the interposition of a 0.1 m thickness insulation support.
- 2. Put the induction coil on horizontal direction. (X direction)
- 3. Recorded the test result as shown in following table.
- 4. Rotated the induction coil by 90° (Y direction) then repeat step 3.
- 5. Rotated the induction coil by 90 $^{\circ}$ (Z direction) then repeat step 3.

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Test conditions:

Field Strength: 1A/m Power Freq.: 50Hz Orientation: X, Y, Z

Orientation	Field	Result (Pass/Fail)	Remark
X	1A	Pass	No any function degraded during the tests.
Y	1A	Pass	No any function degraded during the tests.
Z	1A	Pass	No any function degraded during the tests.

Date of Issue: October 4, 2004

Performance & Result:

	Criterion A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.					
	Criterion B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.					
	Criterion C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.					
Oł	Observation: No function degraded during the tests.						

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16 VOLTAGE DIPS / SHORT INTERRUPTIONS

Port : AC mains

Basic Standard: IEC/EN 61000-4-11

Requirement: PHASE ANGLE 0, 45, 90, 135, 180, 225, 270, 315 degrees

Date of Issue: October 4, 2004

Test Interval : Min. 10 sec.
Tested by : Jason Lee

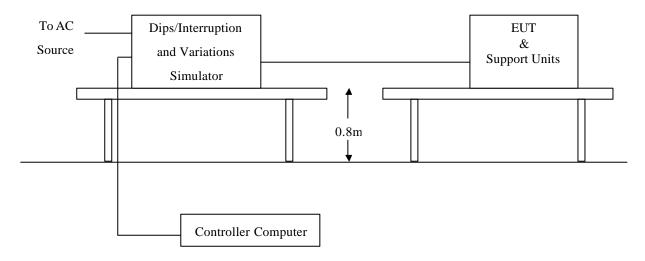
Temperature : 20°C **Humidity** : 59%

Pressure : 1012mbar

Voltage	Test Level % U _T	Reduction (%)	Duration (periods)	Performance Criterion	
Dips	<5	>95	0.5	В	
	70	30	25	C	

Voltage Interceptions —	Test Level % U _T	Reduction (%)	Duration (periods)	Performance Criterion	
	<5	>95	250	С	

Block Diagram of Test Setup:



Test Procedure:

- 1. The EUT and support units were located on a wooden table, 0.8 m away from ground floor.
- 2. Set the parameter of tests and then Performed the test software of test simulator.
- 3. Changed Condition to occur at 0 degree crossover point of the voltage waveform.
- 4. Recorded the test result in test record form.

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Test conditions:

The duration with a sequence of three dips/interruptions with interval of 10 sec. minimum (Between each test event)

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Voltage Dips:

Test Level % U _T	Reduction (%)	Duration (periods)	Observation	Meet Performance Criterion
0	100	0.5	Normal	A
70	30	25	Normal	A

Voltage Interruptions:

Test Level % U _T	Reduction (%)	Duration (periods)	Observation	Meet Performance Criterion
0	100	250	EUT shut down, but EUT can be auto recovered after it restart.	С

Note: "Normal" means no any functions degrade during and after the test.

Performance & Result:

Criterion A: The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.

Criterion B: The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of

performance is however allowed.

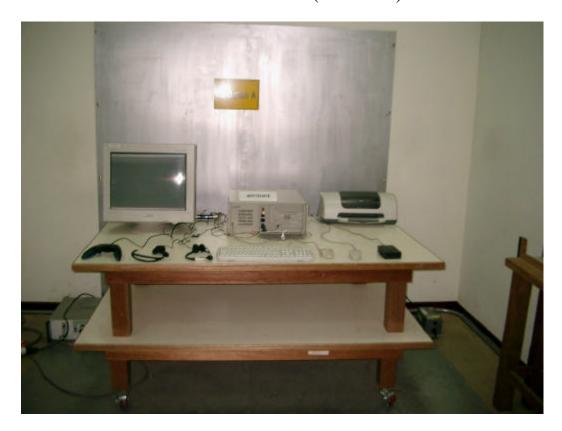
Criterion C: Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

⊠ PASS	☐ FAIL				
Observation: No function degraded during the tests.					

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APPENDIX I - PHOTOGRAPHS OF TEST SETUP

LINE CONDUCTED EMISSION TEST (EN 55022)





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COMMON MODE CONDUCTED EMISSION TEST





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RADIATED EMISSION TEST



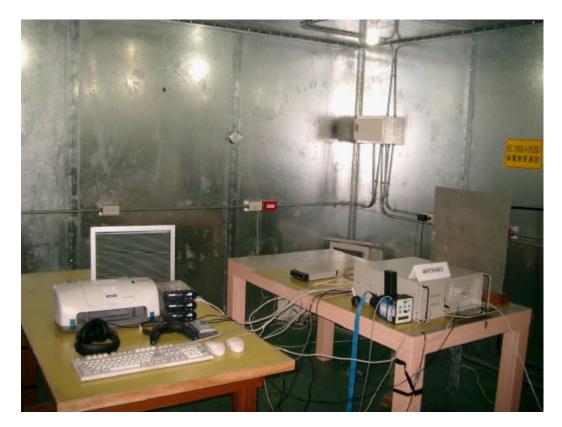


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POWER HARMONIC & VOLTAGE FLUCTUATION / FLICKER TEST



ELECTROSTATIC DISCHARGE TEST

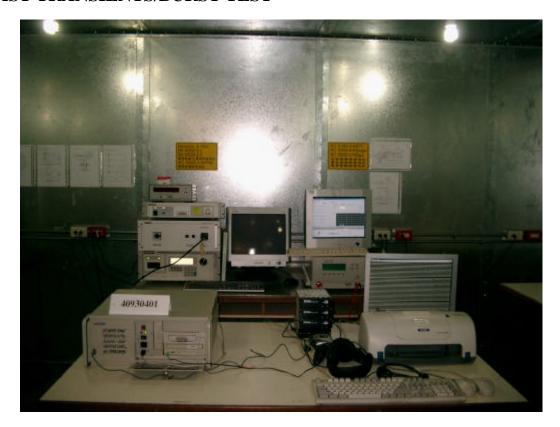


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RADIATED ELECTROMAGNETIC FIELD TEST



FAST TRANSIENTS/BURST TEST



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(IEC 61000-4-4 FOR I/O)



SURGE IMMUNITY TEST



Page 46 Rev. 00

CONDUCTED DISTURBANCE, INDUCED BY RADIO-FREQUENCY FIELDS TEST



(IEC 61000-4-6 FOR I/O)



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POWER FREQUENCY MAGNETIC FIELD IMMUNITY TEST



VOLTAGE DIPS / INTERRUPTION TEST

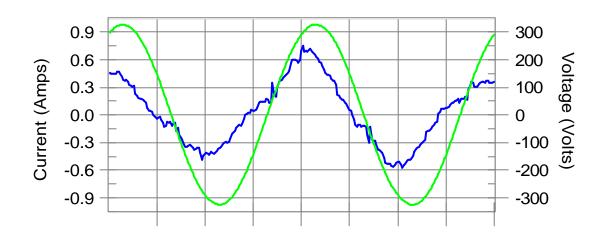


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APPENDIX II – TEST RESULT OF EN 61000-3-3

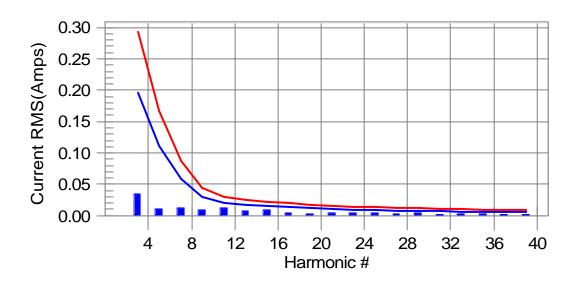
Test Result: Pass Source qualification: Normal

Current & voltage waveforms



Harmonics and Class D limit line

European Limits



Test result: PassWorst harmonic was #15 with 43.13 % of the limit.

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Test Result: Pass Source qualification: Normal

Highest parameter values during test:

V_RMS (Volts): 230.34

 I_Peak (Amps):
 0.756
 I_RMS (Amps):
 0.306

 I_Fund (Amps):
 0.334
 Crest Factor:
 2.480

 Power (Watts):
 62
 Power Factor:
 0.877

Harm#	Harms(avg)	100%Limit	%of Limit	Harms(max)	150%Limit	%of Limit	Status
2	0.000						
3	0.033	0.196	17.0	0.034	0.294	11.64	Pass
4	0.000						
5	0.011	0.111	9.6	0.011	0.167	6.81	Pass
6	0.000						
7	0.011	0.058	18.9	0.012	0.088	13.30	Pass
8	0.000						
9	0.009	0.029	29.8	0.009	0.044	21.66	Pass
10	0.000						
11	0.011	0.020	53.4	0.013	0.031	41.92	Pass
12	0.000						
13	0.007	0.017	40.9	0.008	0.026	29.80	Pass
14	0.000						_
15	0.009	0.015	59.6	0.010	0.022	43.13	Pass
16	0.000		20.4			22.52	_
17	0.004	0.013	29.1	0.004	0.020	22.50	Pass
18	0.000	0.040	05.0	0.000	0.040	40.45	D
19	0.003	0.012	25.6	0.003	0.018	18.45	Pass
20 21	0.000 0.004	0.011	41.3	0.005	0.016	30.63	Pass
21	0.004	0.011	41.3	0.005	0.010	30.03	Fa55
23	0.000	0.010	31.1	0.005	0.015	31.00	Pass
23 24	0.000	0.010	31.1	0.003	0.013	31.00	газэ
25	0.003	0.009	32.8	0.004	0.013	31.94	Pass
26	0.000	0.003	32.0	0.004	0.013	31.34	1 433
27	0.003	0.008	32.2	0.003	0.013	26.75	Pass
28	0.000	0.000		0.000	0.0.0		
29	0.004	0.008	47.1	0.004	0.012	34.68	Pass
30	0.000						
31	0.001	0.007	14.6	0.002	0.011	14.10	Pass
32	0.000						
33	0.002	0.007	29.6	0.002	0.010	21.26	Pass
34	0.000						
35	0.002	0.006	31.0	0.002	0.010	22.32	Pass
36	0.000						
37	0.001	0.006	17.3	0.001	0.009	13.97	Pass
38	0.000						_
39	0.002	0.006	27.7	0.002	0.009	20.25	Pass
40	0.000						

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Test Result: Pass Source qualification: Normal

Highest parameter values during test:

Voltage (Vrms): 230.34

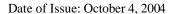
 I_Peak (Amps):
 0.756
 I_RMS (Amps):
 0.306

 I_Fund (Amps):
 0.334
 Crest Factor:
 2.480

 Power (Watts):
 62
 Power Factor:
 0.877

Harm#	Harmonics V-rms	Limit V-rms	% of Limit	Status
2	0.167	0.459	36.37	ОК
3	0.392	2.071	18.93	OK
4	0.062	0.460	13.44	ок
5	0.061	0.920	6.67	OK
6	0.167	0.461	36.17	OK
7	0.062	0.689	8.97	OK
8	0.058	0.459	12.62	OK
9	0.079	0.460	17.23	OK
10	0.060	0.461	12.98	OK
11	0.187	0.230	81.26	OK
12	0.039	0.230	17.13	OK
13	0.067	0.230	28.98	OK
14	0.028	0.230	12.14	OK
15	0.046	0.230	20.17	OK
16	0.035	0.230	15.22	OK
17	0.031	0.230	13.64	OK
18	0.072	0.230	31.17	OK
19	0.027	0.230	11.69	OK
20	0.046	0.230	20.00	OK
21	0.049	0.230	21.54	OK
22	0.046	0.230	19.90	OK
23	0.157	0.230	68.40	OK
24	0.053	0.230	22.98	OK
25	0.170	0.230	74.07	OK
26	0.068	0.230	29.75	OK
27	0.090	0.230	39.05	OK
28	0.081	0.230	35.08	OK
29	0.053	0.230	22.83	OK
30	0.090	0.230	39.25	OK
31	0.022	0.230	9.69	OK
32	0.020	0.230	8.51	OK
33	0.020	0.230	8.87	OK
34	0.015	0.230	6.32	OK
35	0.025	0.230	10.69	OK
36	0.016	0.230	7.04	ОК
37	0.019	0.230	8.41	OK
38	0.015	0.230	6.52	OK
39	0.016	0.230	6.96	ОК
40	0.015	0.230	6.42	OK

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Test Result: Pass Status: Test Completed

Pst_i and limit line

European Limits



Time is too short for Plt plot

Parameter values recorded during the test:

Vrms at the end of test (Volt):	229.71			
Highest dt (%):	-0.27	Test limit (%):	3.14	Pass
Time(mS) > dt:	0.0	Test limit (mS):	500.0	Pass
Highest dc (%):	0.40	Test limit (%):	3.14	Pass
Highest dmax (%):	0.57	Test limit (%):	3.80	Pass
Highest Pst (10 min. period):	0.162	Test limit:	0.950	Pass
Highest Plt (2 hr. period):	0.071	Test limit:	0.617	Pass

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APPENDIX III - TEST RESULT OF FINAL DATAS

Conducted Emission Plot

Radiated Emission Data

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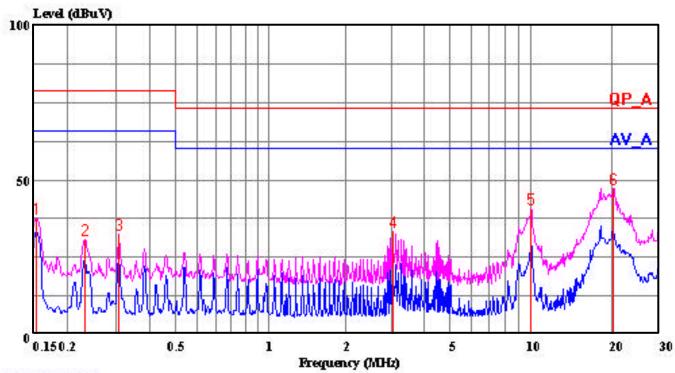


No. 199, Chung Sheng Road, Hsin Tien City, Taipei, Taiwan, R.O.C.

Page: 1

Tel:02-2217-0894 Fax:02-2217-1029

Data#: 18 File#: 40930401C.EMI Date: 2004-09-30 Time: 18:46:50



(Conduction A)

Trace: 17 16 Ref Trace:

Condition: LINE

Report No. : 40930401 Test Engr. : JOHN YEN

: AAEON Technology Inc. Company : ARS-640M-845-X30-W EUT Test Config : EUT / ALL PERIPHERALS Type of Test: EN 55022 CLASS A

Mode of Op. : 2048X1536, VF=75Hz (Worst)

	Freq	Read Level	Factor	Level	Limit Line	Over Limit	Remark
	MHz	dBuV	dB	dBuV	dBuV	dB	
1	0.153	37.63	0.11	37.74	79.00	-41.26	Peak
2	0.232	30.63	0.11	30.74	79.00	-48.26	Peak
3	0.310	32.29	0.12	32.41	79.00	-46.59	Peak
4	3.140	33.07	0.23	33.30	73.00	-39.70	Peak
5	10.125	40.35	0.51	40.86	73.00	-32.14	Peak
6	20.270	46.41	0.89	47.30	73.00	-25.70	Peak

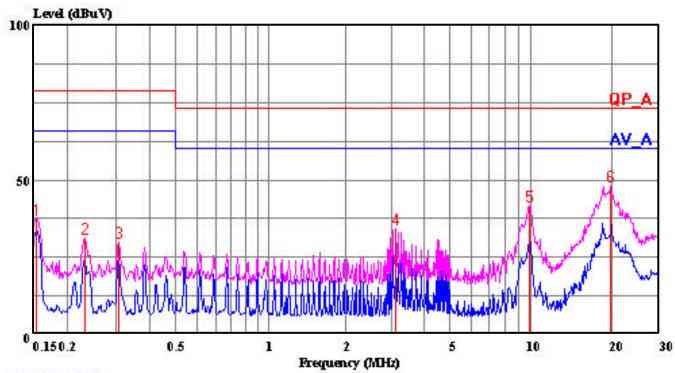


No. 199, Chung Sheng Road, Hsin Tien City, Taipei, Taiwan, R.O.C.

Page: 1

Tel:02-2217-0894 Fax:02-2217-1029

Data#: 15 File#: 40930401C.EMI Date: 2004-09-30 Time: 18:42:22



(Conduction A)

Trace: 14 13 Ref Trace:

Condition: NEUTRAL Report No. : 40930401 Test Engr. : JOHN YEN

: AAEON Technology Inc. Company : ARS-640M-845-X30-W EUT Test Config : EUT / ALL PERIPHERALS

Type of Test: EN 55022 CLASS A

Mode of Op. : 2048X1536, VF=75Hz (Worst)

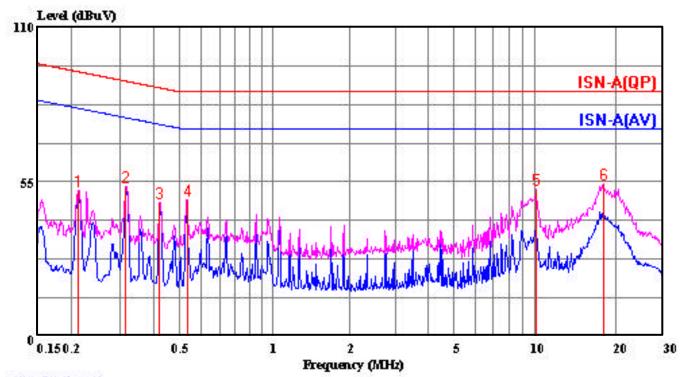
	Freq	Read Level	Factor	Level	Limit Line	Over Limit	Remark	
	MHz	dBuV	dB	dBuV	dBuV	dB		
1	0.153	37.29	0.11	37.40	79.00	-41.60	Peak	
2	0.230	30.89	0.11	31.00	79.00	-48.00	Peak	
3	0.307	29.89	0.12	30.01	79.00	-48.99	Peak	
4	3.224	33.77	0.24	34.01	73.00	-38.99	Peak	
5	9.966	41.25	0.51	41.76	73.00	-31.24	Peak	
6	19.950	47.19	0.87	48.07	73.00	-24.93	Peak	



No. 199, Chung Sheng Road, Hsin Tien City, Taipei, Taiwan, R.O.C.

Tel:02-2217-0894 Fax:02-2217-1029

Data#: 24 File#: 40930401C.EMI Date: 2004-09-30 Time: 19:06:33



(Conduction A)

Trace: 23 22 Ref Trace:

Condition:

Report No. : 40930401 Test Engr. : JOHN YEN

Company : AAEON Technology Inc.
EUT : ARS-640M-845-X30-W
Test Config : EUT / ALL PERIPHERALS
Type of Test: EN 55022 CLASS A
Mode of Op. : ISN 10Mbps (Worst)

Page: 1

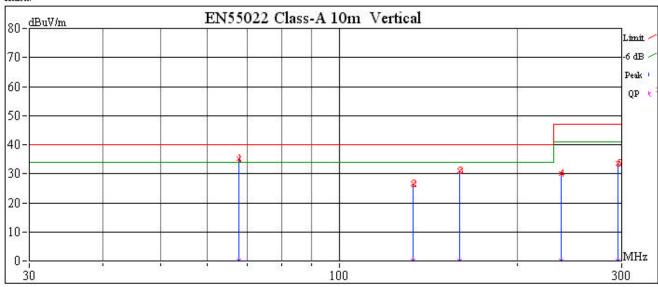
	Freq	Read Level	Factor	Level	Limit Line	Over Limit	Remark	
	MHz	dBuV	dB	dBuV	dBuV	dB		
1	0.211	41.45	10.30	51.75	94.18	-42.43	Peak	
2	0.317	43.19	10.30	53.49	90.80	-37.31	Peak	
3	0.421	37.21	10.30	47.51	88.42	-40.91	Peak	
4	0.532	38.31	10.29	48.60	87.00	-38.40	Peak	
5	10.233	42.33	10.20	52.53	87.00	-34.47	Peak	
6	18.039	44.09	10.20	54.29	87.00	-32.71	Peak	

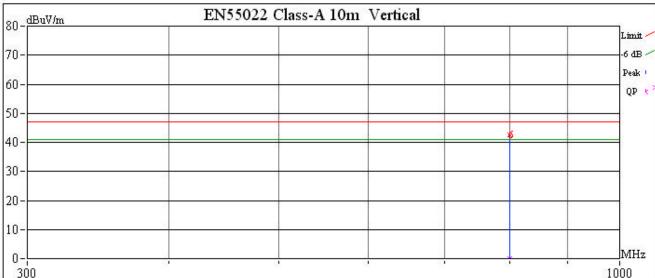




Custom Name: AAEON Technology Inc. Model Name: ARS-640M-845-X30-W Test Mode: 2048X1536, VF=75Hz (Worst) Project No.: 40930401 Engineer Name: Matt Hsu Date: 2004-09-30

Index:





	Freq(MHz)	Peak(dBuV/m)	QP(dBuV/m)	Margin(dB)	Limit(dBuV/m)	Reading(dBuV)	Factor(dB)	Height	Degree	Comment
1	67.7810	35.29		-4.71	40.00	51.10	-15.81	100	0	
2	133.3600	26.65	6	-13.35	40.00	36.32	-9.67	100	0	
3	159.7300	30.98		-9.02	40.00	41.65	-10.67	100	0	
4	237.3000	29.98		-17.02	47.00	38.65	-8.67	100	0	
5	295.5500	33.50	ë S	-13.50	47.00	40.25	-6.75	100	0	
6	800.3200	42.54	DA	-4.46	47.00	40.11	2.43	100	0	
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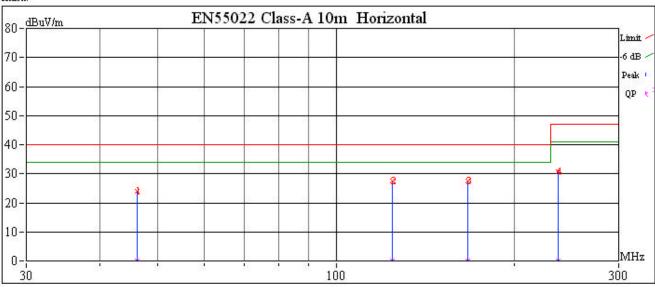


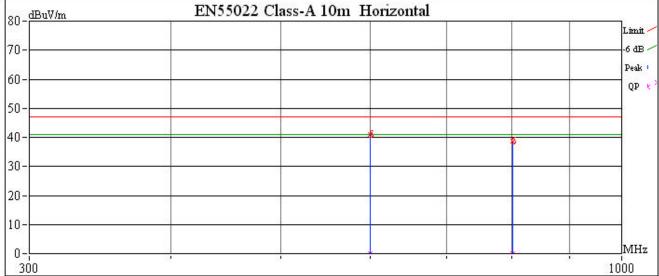


Custom Name: AAEON Technology Inc. Model Name: ARS-640M-845-X30-W Test Mode: 2048X1536, VF=75Hz (Worst)

Project No.: 40930401 Engineer Name: Matt Hsu Date: 2004-09-30

Index:





	Freq(MHz)	Peak(dBuV/m)	QP(dBuV/m)	Margin(dB)	Limit(dBuV/m)	Reading(dBuV)	Factor(dB)	Height	Degree	Comment
1	46.1800	23.87		-16.13	40.00	36.99	-13.12	397	0	
2	124.4900	27.52	6	-12.48	40.00	36.85	-9.33	397	0	
3	166.7300	27.48		-12.52	40.00	38.44	-10.96	397	0	
4	237.3000	30.85		-16.15	47.00	39.52	-8.67	397	0	
5	599,4000	40.92	e 	-6.08	47.00	40.21	0.71	100	0	
6	800.9000	38.65	0A	-8.35	47.00	36.21	2.44	218	0	
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			No.			-				